

SEMI Staff Report



SEMI China Standards Staff

September 22, 2021

v2



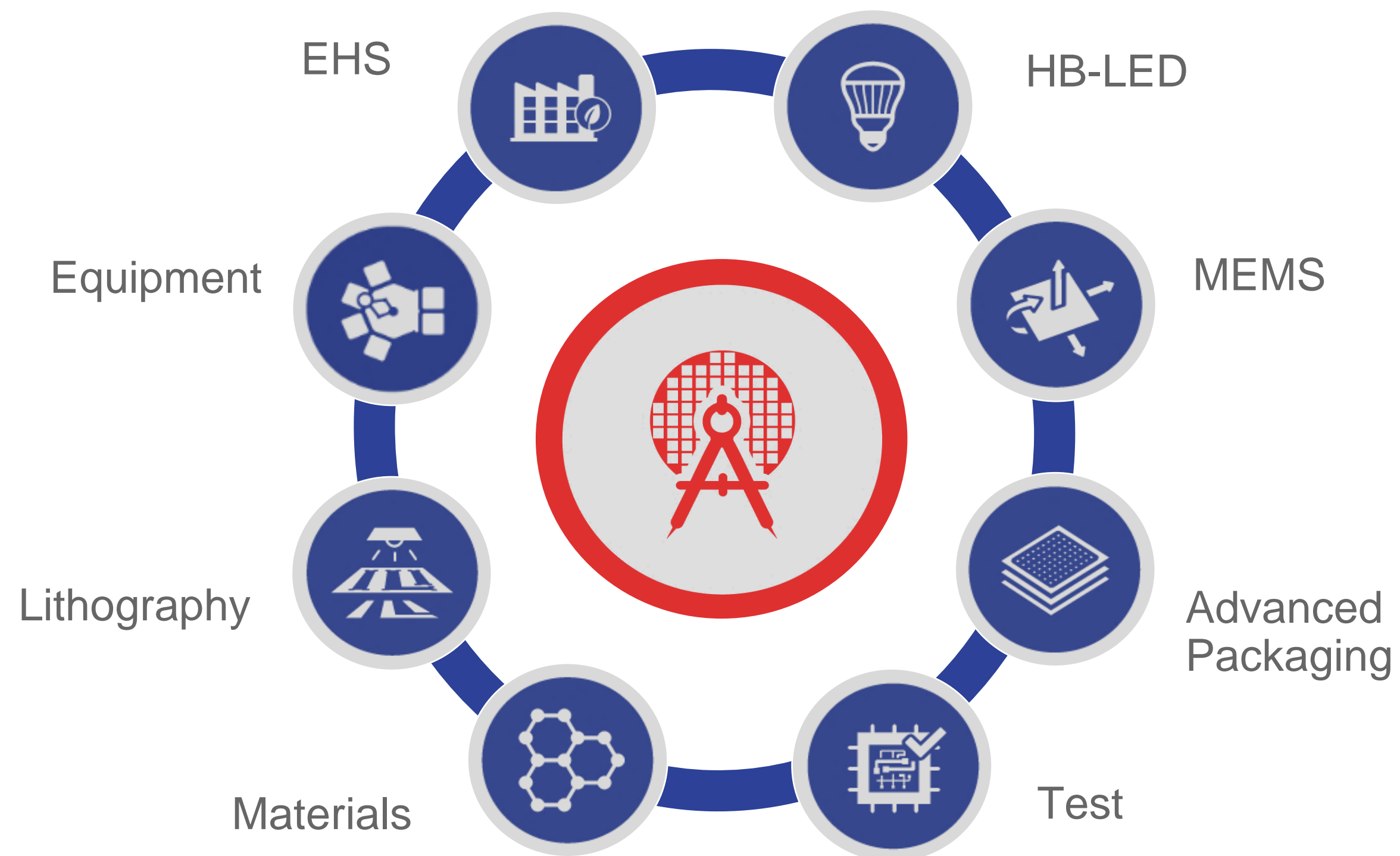
CONNECT - COLLABORATE - INNOVATE - GROW - PROSPER



OUTLINE

- SEMI International Standards Overview
- SEMI Standards Publications
- 2021 Critical Dates for SEMI Standards Ballots
- NARSC Members
- Organization chart
- Major Activity

SEMI International Standards



- **1049** published SEMI Standards & Safety Guidelines
- **5000+** volunteer experts
 - 20 global Technical Committees
 - 200+ global Task Forces
- **2000+** participating companies
- **International presence**
 - United States | Japan | Europe | Taiwan | Korea | China
- **Benefits of using SEMI Standards**
 - Improved supply chain communication
 - Increased manufacturing efficiencies
 - Accelerated product development

Standards Technical Committes

Automated Test Equipment
Automation Technology
Compound Semiconductor Materials
Environmental Health & Safety Facilities
FPD Materials & Components
FPD Metrology
Gases
High-Brightness LED
Information & Control

Liquid Chemicals
MEMS / NEMS
Metrics
Micropatterning
Photovoltaic
Photovoltaic Materials
Physical Interfaces & Carriers
Silicon Wafer
Traceability
3D Packaging and Integration

Charter: <http://downloads.semi.org/web/wstdsbal.nsf/StdCharters>

SEMI Standards Publications

- July 2021 Cycle
 - New Standards: 3
 - Revised Standards: 1
 - Reapproved Standards: 3
 - Withdrawn Standards: 0
- Total SEMI Standards in portfolio: 1049
 - Includes 288 Inactive Standards
- Total SEMI Standards for CSM : 26
- Total SEMI Standards for HB-LED: 13

2021 Critical Dates for SEMI Standards Ballots

2021	Ballot Submission	Voting Period Starts	Voting Period Ends
Cycle 1	1月5日	1月19日	2月18日
Cycle 2	1月29日	2月10日	3月12日
Cycle 3	3月9日	3月23日	4月22日
Cycle 4	4月14日	4月28日	5月28日
Cycle 5	5月18日	6月1日	7月1日
Cycle 6	8月3日	8月17日	9月16日
Cycle 7	9月1日	9月15日	10月15日
Cycle 8	10月8日	10月22日	11月22日
Cycle 9	11月16日	11月30日	12月30日

NARSC Member

Co-chairs (Compound Semiconductor Materials TC)



Jiangbo Wang

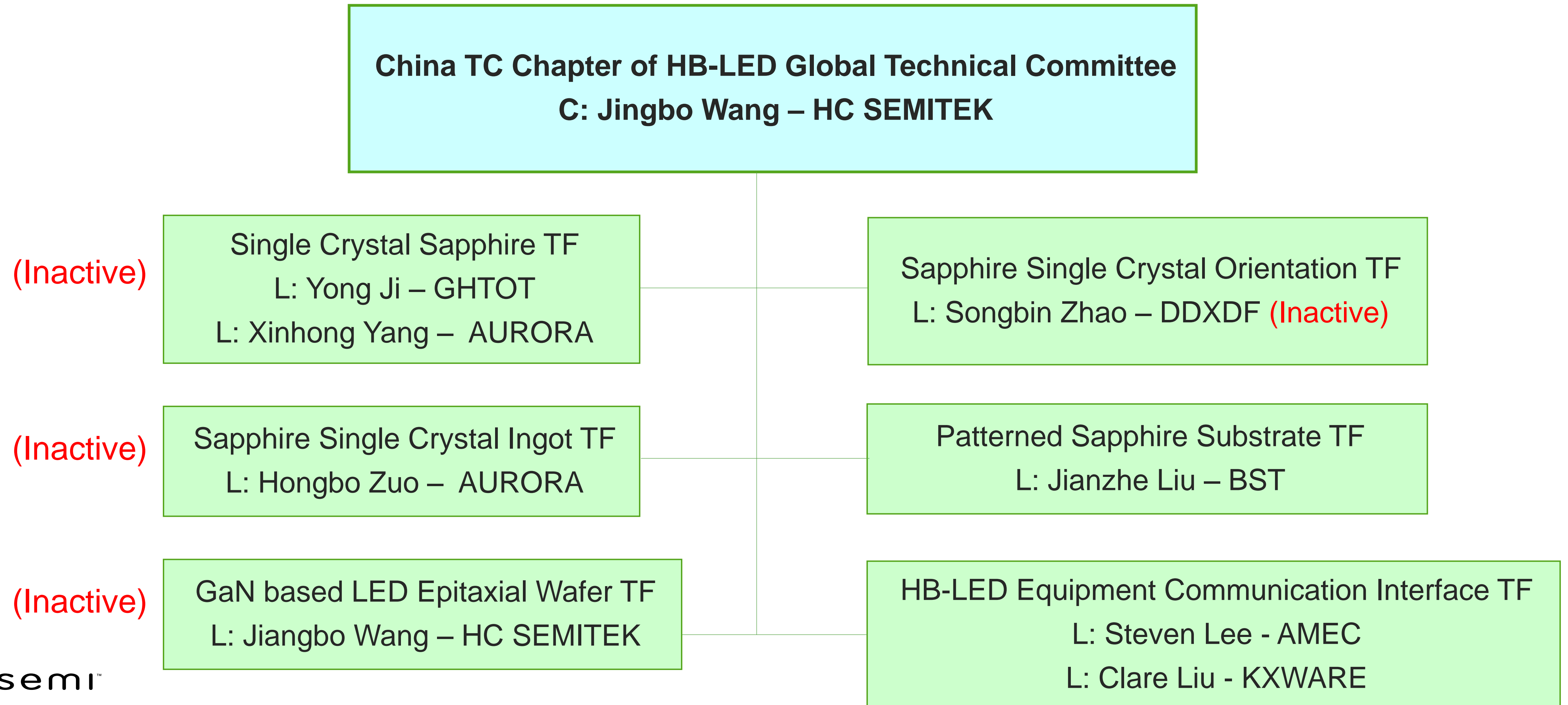
Vice president of HC-SemiTek



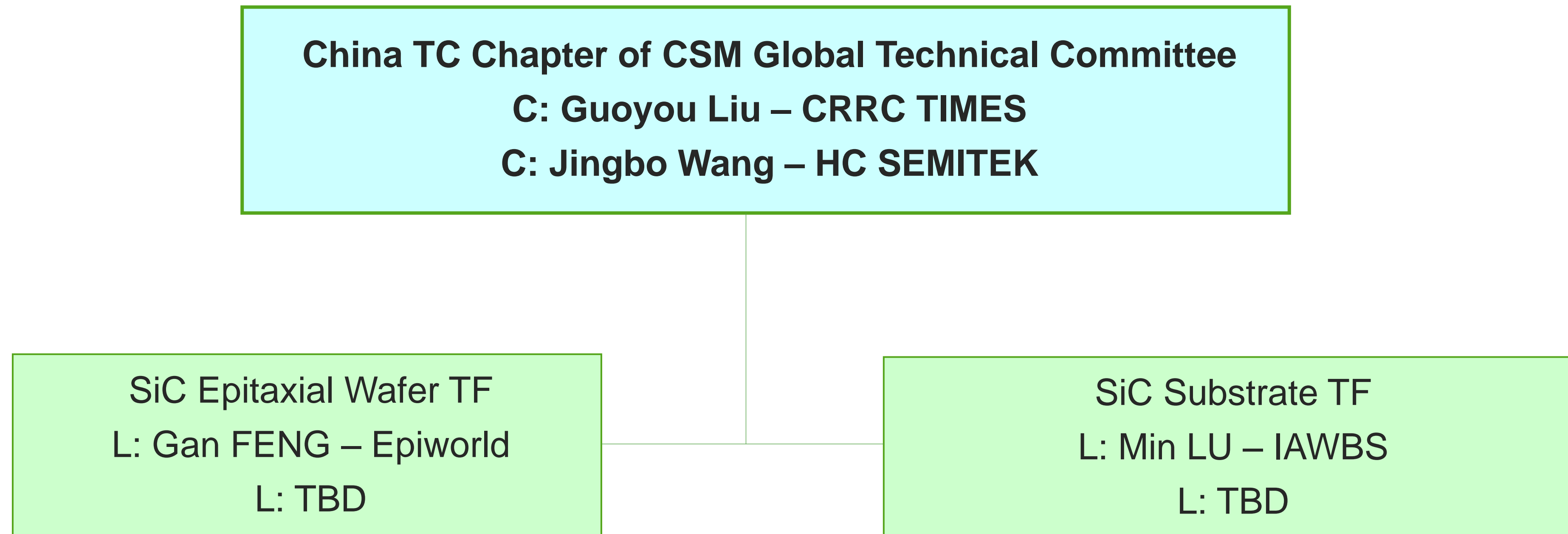
Guoyou Liu

Chief Engineer of CRRC TIMES

Organization Chart for China HB-LED Committee



Organization Chart for China Compound Semiconductor Material Committee



Major Activities -- HB-LED and Compound Semiconductor Materials Chapter

HB-LED and Compound Semiconductor Materials Joint TC Chapter Spring meeting was completed (Mar.16, F2F).

- 3 New SNARF were approved by TC and GCS
 - 6768, New Standard: Test Method for Micropipe Density of Silicon Carbide Wafer by Laser Reflection
 - 6767, New Standard: Test Method for Flatness of Silicon Carbide Wafers by Optical Interference
 - 6769, New Standard: Test Method for Residual Stress of Silicon Carbide Wafers by Photoelastic
- 6589, revision to HB4-0913 (Reapproved 0419) passed reviewed, forward to A&R, **PASSED**, pending publication
- 6371C, New Standard: Test Method for Determining Geometrical Parameters of Patterns on Patterned Sapphire Substrate approved to join cycle ballots

Thank you!